

**Search Notes**

Application/Control No.

10/630,243

Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

2635

**SEARCHED**

Class	Subclass	Date	Examiner
340	825.69	1/6/2006	NN
340	825.79	1/6/2006	NN
340	5.2+	1/6/2006	NN
340	5.7+	1/6/2006	NN
341	50	1/6/2006	NN
341	176	1/6/2006	NN
348	734	1/6/2006	NN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>SAME AS</b>	<b>ABOVE</b>	<b>1/6/2006</b>	<b>NN</b>

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search East: USPAT; US-PUBS; EPO; JPO and Derwent. (UPDATED SEARCH).	1/6/2006	NN